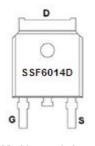
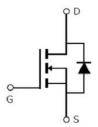


Main Product Characteristics:

V _{DSS}	60V
R _{DS} (on)	12mΩ(typ.)
I _D	60A







DPAK

Marking and pin
Assignments

Schematic diagram

Features and Benefits:

- Advanced trench MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery



Description:

It utilizes the latest trench processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

Absolute Max Rating:

Symbol	Parameter	Max.	Units		
I _D @ T _C = 25°C	© T _C = 25°C Continuous Drain Current, V _{GS} @ 10V ①				
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V ①	42	Α		
I _{DM}	Pulsed Drain Current ②				
D @T - 25°C	Power Dissipation ③	115	W		
P _D @T _C = 25°C	Linear Derating Factor	0.74	W/°C		
V _{DS}	Drain-Source Voltage	60	V		
V _{GS}	Gate-to-Source Voltage	± 20	V		
Eas	Single Pulse Avalanche Energy @ L=0.3mH	235	mJ		
I _{AS}	Avalanche Current @ L=0.3mH	39	Α		
T _J T _{STG}	Operating Junction and Storage Temperature Range	-55 to + 150	°C		



Thermal Resistance

Symbol	Characterizes	Тур.	Max.	Units
R _{θJC}	Junction-to-case ③	1.31	_	°C/W
R _{θJA}	Junction-to-ambient ④	_	62	°C/W

Electrical Characteristics@ T_A =25 $^{\circ}$ C unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions	
V _{(BR)DSS}	Drain-to-Source breakdown voltage	60	_	_	V	V _{GS} = 0V, ID = 250μA	
R _{DS(on)}	Static Drain-to-Source on-resistance	_	12	14	mΩ	V _{GS} =10V,I _D = 30A	
V _{GS(th)}	Gate threshold voltage	1.0	_	3.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	
I _{DSS}	Drain-to-Source leakage current	_	_	1	μA	$V_{DS} = 60V, V_{GS} = 0V$	
	Cata to Source forward looked	_	_	100	nA	V _{GS} =20V	
I _{GSS}	Gate-to-Source forward leakage	_	_	-100		V _{GS} = -20V	
Qg	Total gate charge	_	45	_		I _D = 30A, V _{DS} =30V, V _{GS} = 10V	
Q _{gs}	Gate-to-Source charge	_	4	_	nC		
Q _{gd}	Gate-to-Drain("Miller") charge	_	15	_			
t _{d(on)}	Turn-on delay time	_	14.6	_		V -40V VDC-20V	
t _r	Rise time	_	14.2	_	no	V_{GS} =10V, VDS=30V, R_L =15 Ω , R_{GEN} =2.5 Ω	
t _{d(off)}	Turn-Off delay time	_	40	_	ns		
t _f	Fall time	_	7.3	_			
Ciss	Input capacitance	_	1480	_		V _{GS} = 0V	
Coss	Output capacitance	_	190	_	pF	V _{DS} = 25V	
C _{rss}	Reverse transfer capacitance	_	135	_		f = 1MHz	

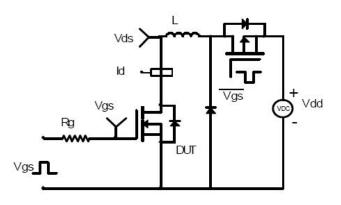
Source-Drain Ratings and Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current		_	60	А	MOSFET symb
	(Body Diode)	_				showing the
Іѕм	Pulsed Source Current	_	_	240	А	integral reverse
	(Body Diode)					p-n junction diode.
V _{SD}	Diode Forward Voltage	_	_	1.3	V	I _S =30A, V _{GS} =0V
t _{rr}	Reverse Recovery Time	_	33	_	ns	T _J = 25°C, I _F =60A,
Q _{rr}	Reverse Recovery Charge	_	61	_	nC	di/dt = 100A/μs

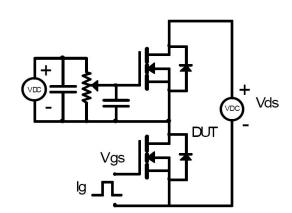


Test Circuits and Waveforms:

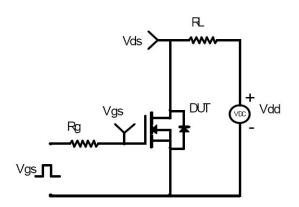
EAS Test Circuit:



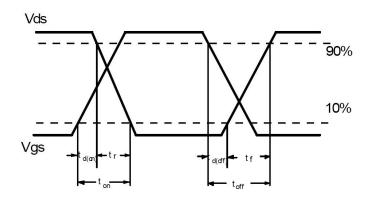
Gate Charge Test Circuit:



Switching Time Test Circuit:



Switching Waveforms:



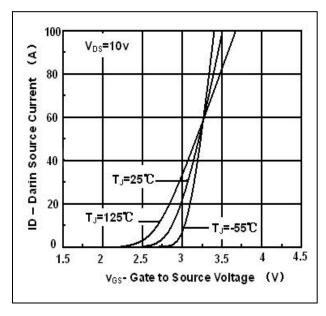
Version: 2.3

Notes:

- ①Calculated continuous current based on maximum allowable junction temperature.
- ②Repetitive rating; pulse width limited by max. junction temperature.
- $\ \ \,$ The power dissipation P_D is based on max. junction temperature, using junction-to-case thermal resistance.
- ④ The value of R_{θJA} is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25$ °C.



Typical Electrical and Thermal Characteristics



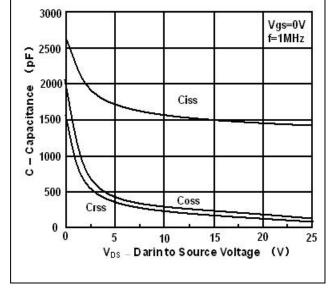


Figure 1. Transfer Characteristic

Figure 2. Capacitance

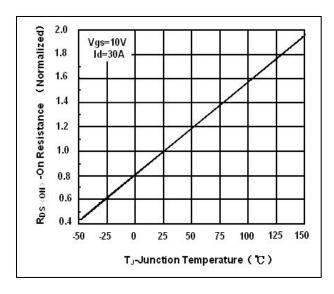


Figure 3. On Resistance vs. Junction Temperature

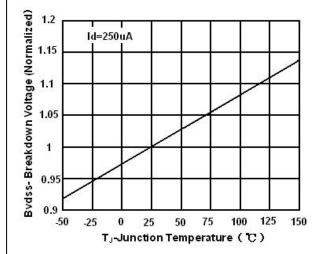
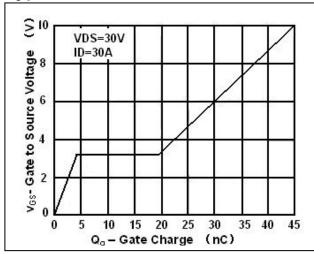
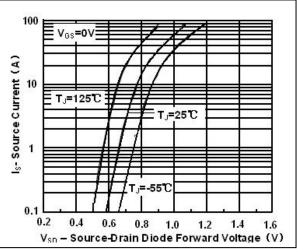


Figure 4. Breakdown Voltage vs. Junction Temperature



Typical Electrical and Thermal Characteristics





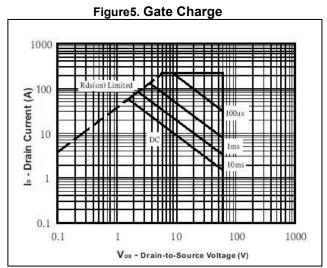


Figure 6. Source-Drain Diode Forward Voltage

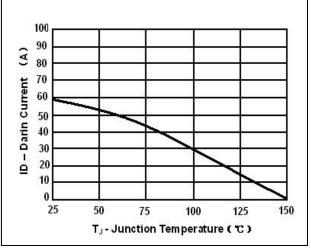


Figure 7. Safe Operation Area

Figure 8. Max Drain Current vs. Junction Temperature

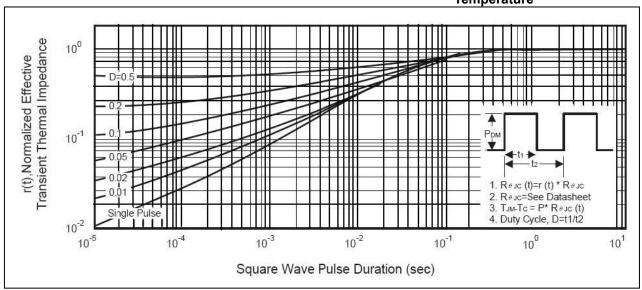
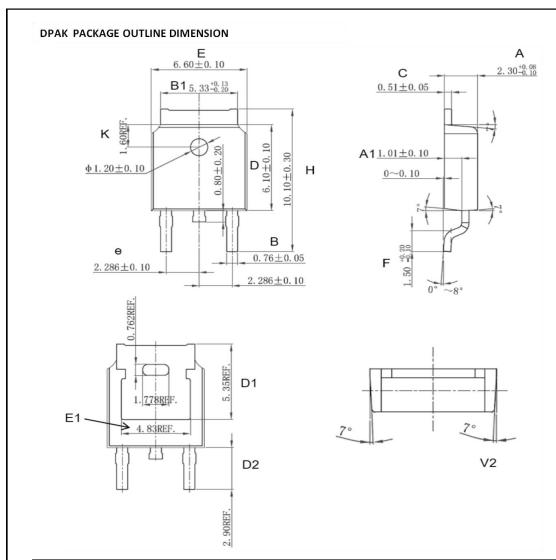


Figure 9. Transient Thermal Impedance Curve



Mechanical Data:



Symbol	Dime	ension In Millim	eters	Dimension In Inches			
Syllibol	Min	Nom	Max	Min	Nom	Max	
Α	2.200	2.300	2.380	0.087	0.091	0.094	
A1	0.910	1.010	1.110	0.036	0.040	0.044	
В	0.710	0.760	0.810	0.028	0.030	0.032	
B1	5.130	5.330	5.460	0.202	0.210	0.215	
С	0.460	0.510	0.560	0.018	0.020	0.022	
D	6.000	6.100	6.200	0.236	0.240	0.244	
D1	5.350 (REF)				0.211 (REF)		
D2		2.900 (REF)		0.114 (REF)			
Е	6.500	6.600	6.700	0.256	0.260	0.264	
E1		4.83 (REF)		0.190 (REF)			
е	2.186	2.286	2.386	0.086	0.090	0.094	
Н	9.800	10.100	10.400	0.386	0.398	0.409	
F	1.400	1.500	1.700	0.055	0.059	0.067	
K		1.600 (REF)		0.063 (REF)			
V2		8º (REF)			8º (REF)		





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